



CTL16PS05-R3

P-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} - 50 V
- Drain-Source On-Resistance
 $R_{DS(ON)} 2\Omega$, at $V_{GS} = -10V$, $I_{DS} = -100mA$
 $R_{DS(ON)} 2\Omega$, at $V_{GS} = -5.0V$, $I_{DS} = -100mA$
- Continuous Drain Current at $T_A=25^\circ C$ $I_D = -160mA$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

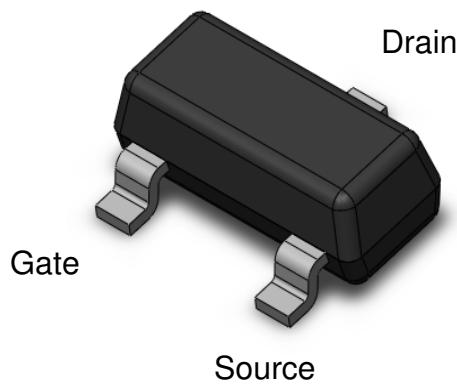
Description

The CTL16PS05-R3 uses high performance Trench Technology to provide excellent $R_{DS(ON)}$ and low gate charge which is suitable for most of the synchronous buck converter applications .

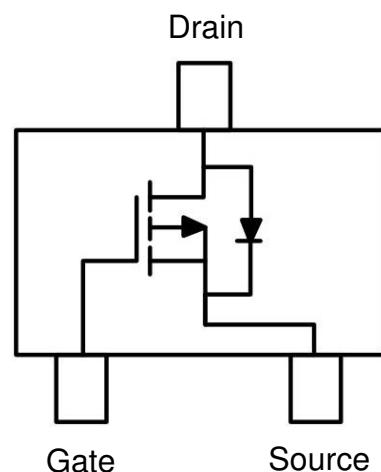
Applications

- Power Management
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch

Package Outline



Schematic





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Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
V_{DS}	Drain-Source Voltage	-50	V	
V_{GS}	Gate-Source Voltage	± 20	V	
I_D	Continuous Drain Current @ $T_A=25^\circ\text{C}$	-0.16	A	1
I_{DM}	Pulsed Drain Current	-0.64	A	1
P_D	Total Power Dissipation @ $T_A=25^\circ\text{C}$	0.22	W	2
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$	
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\Theta JA}$	Thermal Resistance Junction-Ambient ($t=10\text{s}$)		-	555	-	$^\circ\text{C}/\text{W}$	1,4



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Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B_{VDSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D = -250\mu\text{A}$	-50	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = -50\text{V}$, $V_{GS} = 0\text{V}$	-	-	-1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = -10\text{V}$, $I_D = -100\text{mA}$	-	2	5		Fig 4
		$V_{GS} = -5\text{V}$, $I_D = -100\text{mA}$	-	2	6		
$V_{GS(TH)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = -250\mu\text{A}$	-0.8	-	-2.0	V	Fig 5

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{DS} = -5\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$	-	41.5	-	pF	Fig 3
C_{OSS}	Output Capacitance		-	19.5	-		
C_{RSS}	Reverse Transfer Capacitance		-	4	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = -15\text{V}$, $R_L = 50\Omega$, $V_{GS} = -10\text{V}$, $R_G = 25\Omega$,	-	13.7	-	ns	Fig 11 & 12
T_R	Rise Time		-	6.2	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	15.9	-		
T_F	Fall Time		-	2.8	-		
Q_G	Total Gate Charge	$V_{DS} = -40\text{V}$, $V_{GS} = -4.5\text{V}$, $I_D = -0.5\text{A}$	-	2.3	-	nC	Fig 9 & 10
Q_{GS}	Gate-Source Charge		-	2.4	-		
Q_{GD}	Gate-Drain (Miller) Charge		-	0.7	-		



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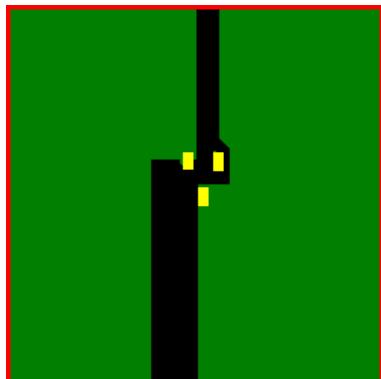
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Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V$, $I_D = -0.1A$			-2.9	V	
I_{SD}	Body Diode Continuous Current				-0.1	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



Actual Size

3. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



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Typical Characteristic Curves

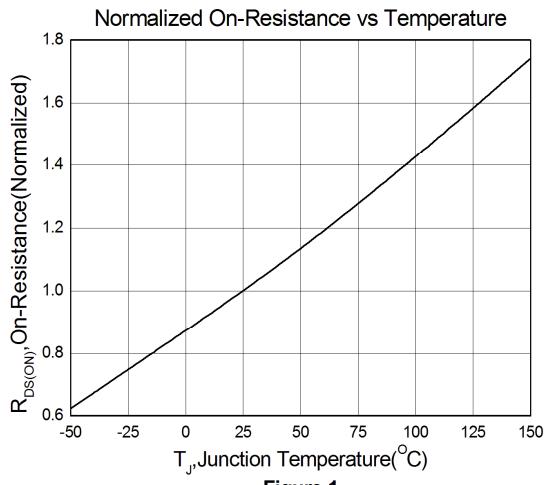


Figure 1

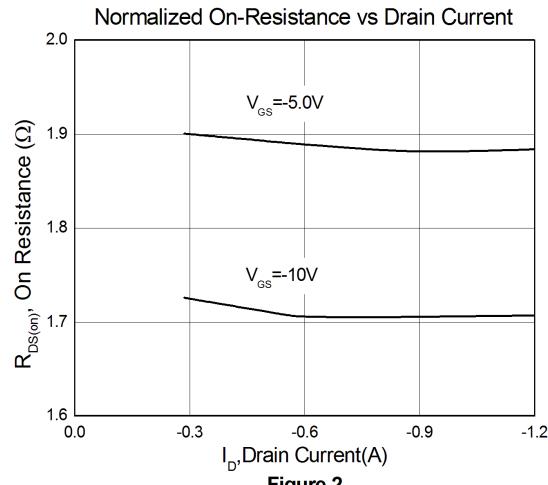


Figure 2

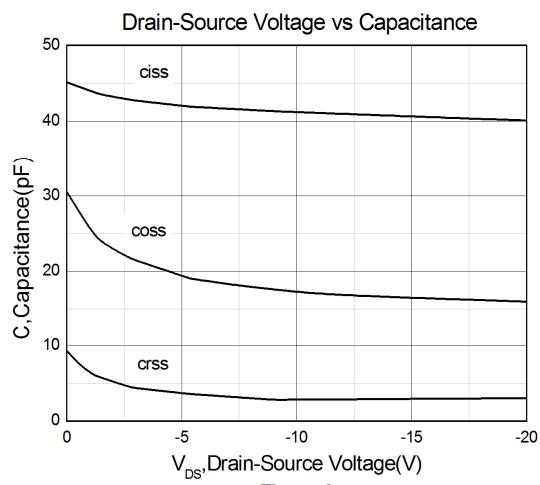


Figure 3

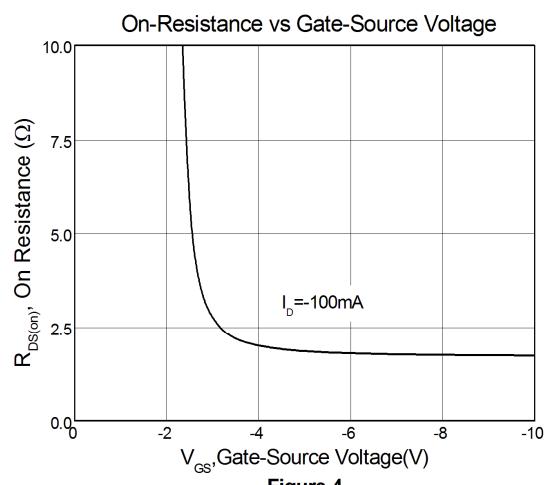


Figure 4

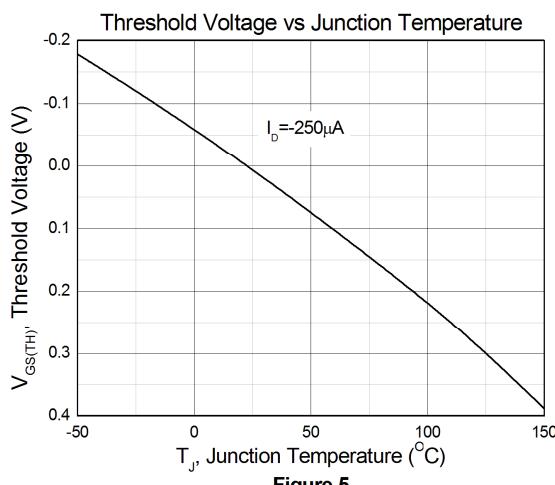


Figure 5

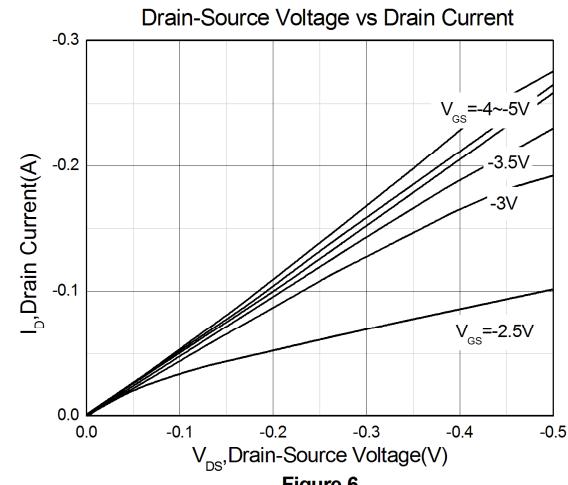


Figure 6



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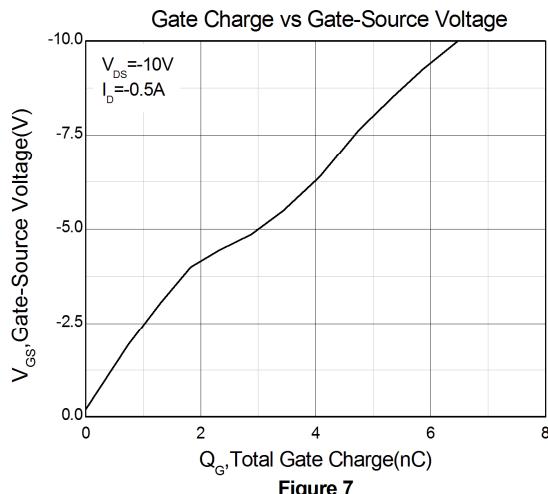


Figure 7

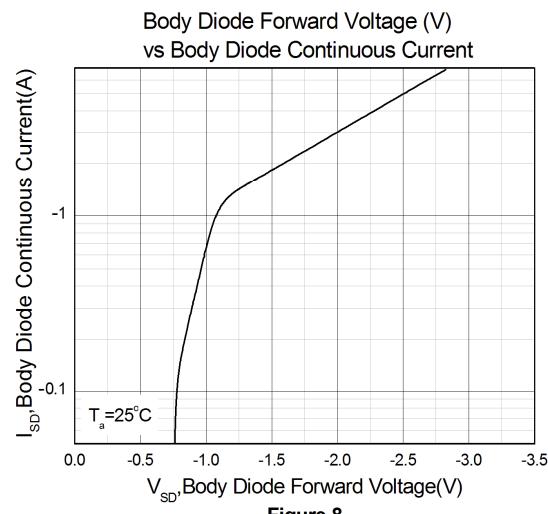


Figure 8



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Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

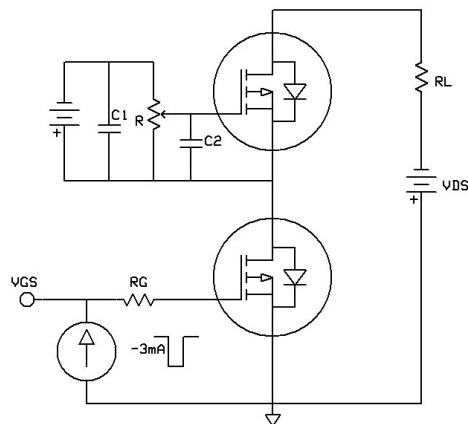


Figure 10: Gate Charge Waveform

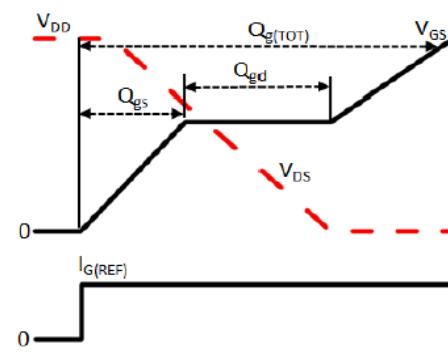


Figure 11: Switching Time Test Circuit

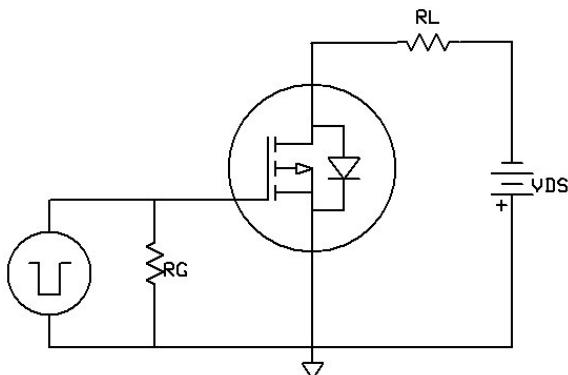
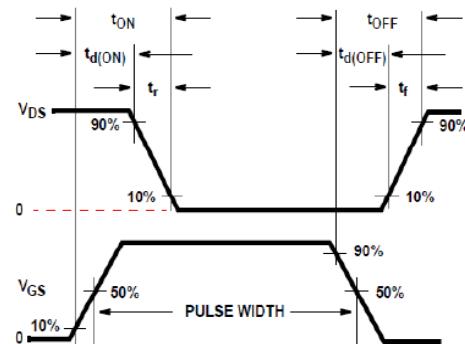


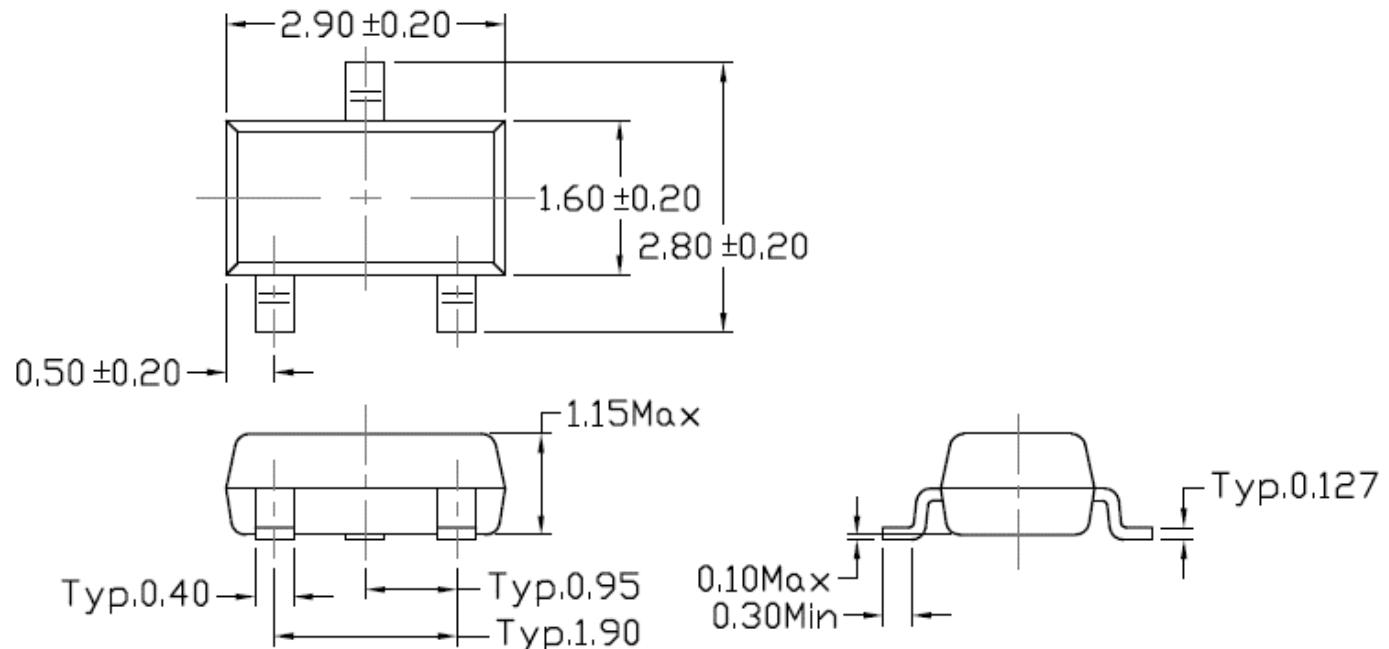
Figure 12: Switching Time Waveform



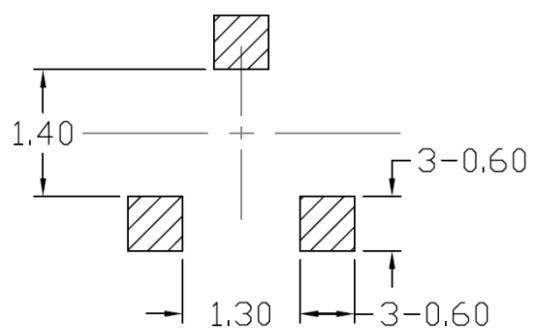


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Package Dimension (SC-59)



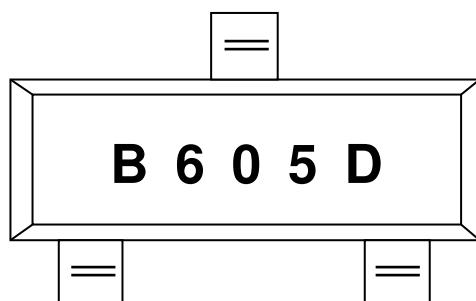
Recommended pad layout for surface mount leadform





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Marking Information



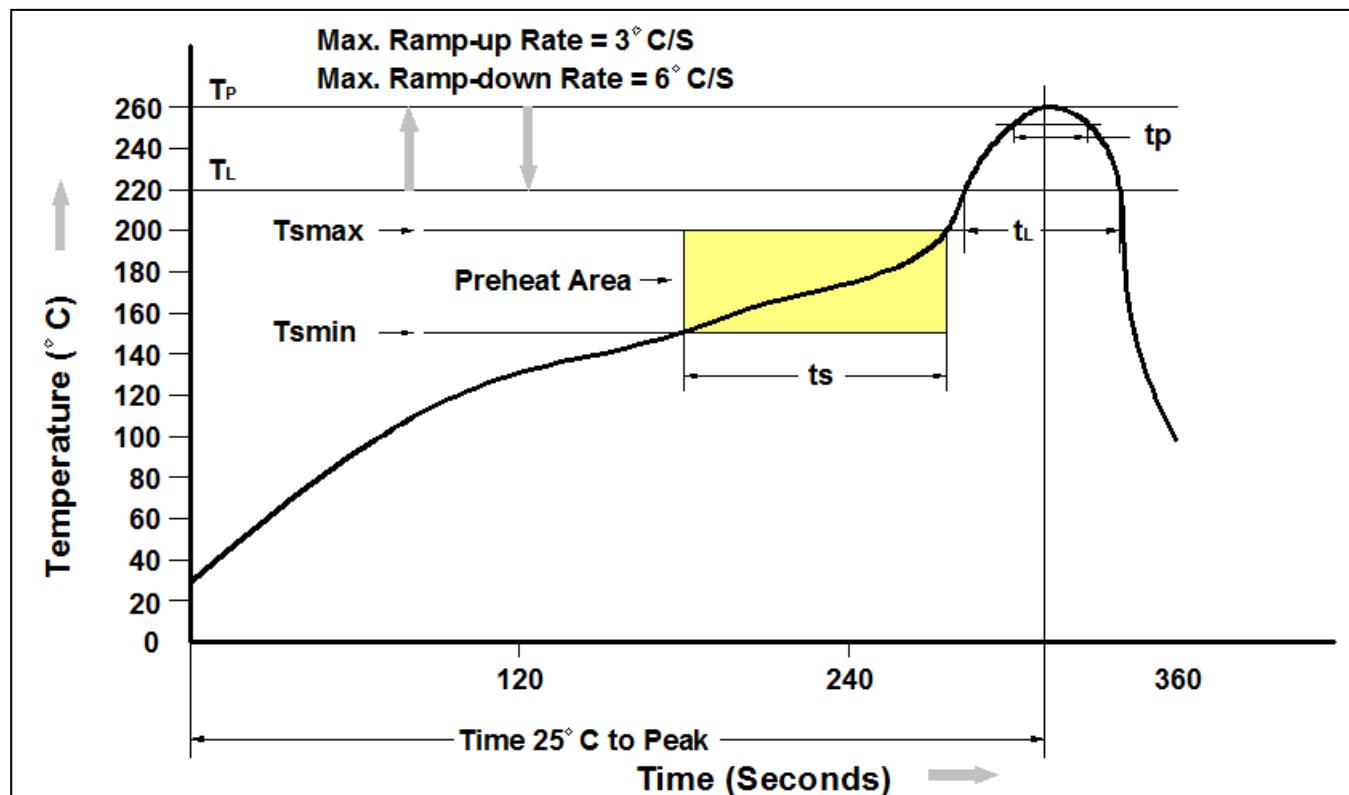
B605D : Device Number

Ordering Information

<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CTL M16PS05-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{smin})	150 °C
Temperature Max. (T _{smax})	200 °C
Time (ts) from (T _{smin} to T _{smax})	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t _P) within 5 °C of 260 °C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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